

## Product Change Notice (PCN)

**Subject:** Wafer Fabrication Site and Datasheet change for Listed Intersil ISL21440\* Products

**Publication Date:** 3/17/2016

**Effective Date:** 6/17/2016

**Revision Description:**

Initial Release

**Description of Change:**

Wafer Fabrication Site and datasheet change for Listed Intersil ISL21440\* Products

Affect Products:

ISL21440IRTZ    ISL21440IUZ    ISL21440IUZ-T13    ISL21440IRTZ-T13

**Reason for Change:**

This notice is to inform you that Intersil has qualified Intersil's Palm Bay, Florida facility for wafer fabrication of the ISL21440\* products. The process technology qualification is complete, the product specific qualification and validation activity is in progress and expected to complete 04/25/16.

Intersil has updated the data sheet (supply current over extreme temperature ranges) to align to the product characteristics and is necessary to maintain product manufacturability in support of customer delivery requirements. Details regarding the data sheet changes are shown in Appendix B. The updated data sheet is available on the Intersil web site at:

<http://www.intersil.com/content/dam/Intersil/documents/isl2/isl21440.pdf>

**Impact on fit, form, function, quality & reliability:**

The product and site qualification plans are designed using JEDEC and other applicable industry standards to confirm there is no impact to form, fit, function, or interchangeability of the product. A summary of the qualification results is included for reference. The ICP Test Report for the Palm Bay fabrication facility is located on Intersil's Environmental web site under Material Sub-Group: "Silicon"; Material "die" and the PDF file is titled Intersil Corporation. <http://www.intersil.com/en/support/environmental.html#WA>;

**Product Identification:**

Product affected by this change is identifiable via Intersil's internal traceability system.

**Qualification status:** In progress, see Appendix A.

**Sample availability:** 3/17/2016

**Device material declaration:** Available upon request

*Questions or requests pertaining to this change notice, including additional data or samples, must be sent to Intersil within 30 days of the publication date.*

**For additional information regarding this notice, please contact your regional change coordinator (below)**

Americas: <a href="mailto:PCN-US@INTERSIL.COM">PCN-US@INTERSIL.COM</a>	Europe: <a href="mailto:PCN-EU@INTERSIL.COM">PCN-EU@INTERSIL.COM</a>	Japan: <a href="mailto:PCN-JP@INTERSIL.COM">PCN-JP@INTERSIL.COM</a>	Asia Pac: <a href="mailto:PCN-APAC@INTERSIL.COM">PCN-APAC@INTERSIL.COM</a>
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**Appendix A:**

Stress / Conditions	Duration	X5043S8IZ2.7A SOICN	X9C103SIZ SOICN	ISL21440IRTZ TDFN	ISL60002DIH325Z SOT23	X9315WMIZ-2.7 MSOP
High Temp Operating Life +125°C	1000 Hrs	N = 234 Acc = 0	N = 156 Acc = 0	QBE	N = 156 Acc = 0	QBE
Moisture Sensitivity Classification		N = 44 Acc = 0 L1 PBFREE	N = 44 Acc = 0 L1 PBFREE	N = 66 Acc = 0 L1 PBFREE	N = 44 Acc = 0 L1 PBFREE	N = 66 Acc = 0 L2 PBFREE
Unbiased HAST +130C / 85% RH	96 Hrs	N = 78 Acc = 0	N = 78 Acc = 0	N = 78 Acc = 0	N = 78 Acc = 0	N = 78 Acc = 0
Temp Cycle +150C / -65C	500 Cy	N = 78 Acc = 0	N = 78 Acc = 0	N = 78 Acc = 0	N = 78 Acc = 0	N = 78 Acc = 0
Biased HAST +130C / 85% RH	96 Hrs	N = 78 Acc = 0	N = 78 Acc = 0	N = 78 Acc = 0	QBE	QBE
High Temperature Storage T <sub>A</sub> = +150C	1000 Hrs	N = 78 Acc = 0	N = 78 Acc = 0	N = 90 Acc = 0	N = 78 Acc = 0	N = 76 Acc = 0

Qualification Completed/Passed
  Qualified by Extension

**Appendix B:**

**From:**

**Analog Specifications** V<sub>+</sub> = +5.0V, V<sub>-</sub> = GND = 0V unless otherwise specified, T<sub>A</sub> = +25°C. Boldface limits apply over the operating temperature range, -40°C to +125°C.

SYMBOL	PARAMETER	TEST CONDITIONS	MIN (Note 10)	TYP (Note 9)	MAX (Note 10)	UNITS
<b>POWER SUPPLY</b>						
V <sub>+</sub>	Supply Voltage Range	V <sub>-</sub> = GND	<b>2.0</b>		<b>11.0</b>	V
I <sub>CC</sub>	Supply Current	IN+ = IN- +80mV, HYST = REF		0.46	0.75	μA
					<b>0.85</b>	μA

**Analog Specifications** V<sub>+</sub> = +3.0V, V<sub>-</sub> = GND = 0V unless otherwise specified, T<sub>A</sub> = +25°C. Boldface limits apply over the operating temperature range, -40°C to +125°C.

SYMBOL	PARAMETER	TEST CONDITIONS	MIN (Note 10)	TYP (Note 9)	MAX (Note 10)	UNITS
<b>V<sub>+</sub> = 3.0V, V<sub>-</sub> = GND = 0V</b>						
I <sub>CC</sub>	Supply Current	IN+ = IN- +80mV, HYST = REF		0.40	0.7	μA
					<b>0.8</b>	μA

**To:**

**Analog Specifications (V<sub>+</sub> = +5.0V)** V<sub>-</sub> = GND = 0V unless otherwise specified, T<sub>A</sub> = +25°C. Boldface limits apply across the operating temperature range, -40°C to +125°C.

SYMBOL	PARAMETER	TEST CONDITIONS	MIN (Note 11)	TYP (Note 10)	MAX (Note 11)	UNIT
<b>POWER SUPPLY</b>						
V <sub>+</sub>	Supply Voltage Range	V <sub>-</sub> = GND	<b>2.0</b>		<b>11.0</b>	V
I <sub>CC</sub>	Supply Current	IN+ = IN- +80mV, HYST = REF		0.46	0.75	μA
					<b>5</b>	μA

**Analog Specifications (V<sub>+</sub> = +3.0V)** V<sub>-</sub> = GND = 0V unless otherwise specified, T<sub>A</sub> = +25°C. Boldface limits apply across the operating temperature range, -40°C to +125°C.

SYMBOL	PARAMETER	TEST CONDITIONS	MIN (Note 11)	TYP (Note 10)	MAX (Note 11)	UNIT
<b>V<sub>+</sub> = 3.0V, V<sub>-</sub> = GND = 0V</b>						
I <sub>CC</sub>	Supply Current	IN+ = IN- +80mV, HYST = REF		0.40	0.7	μA
					<b>5</b>	μA